

## YGMOS Technology Crop.

100V N Channel Enhancement Mode MOSFET 100 V N 沟道增强型 MOS 管

**VDS= 100V**

**RDS(ON), Vgs@10V, Ids@2.0A = 220mΩ**

**RDS(ON), Vgs@4.5V, Ids@1.0A = 240mΩ**

### Features 特性

Advanced trench process technology 高级的加工技术

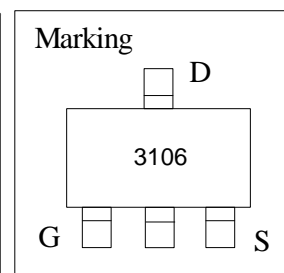
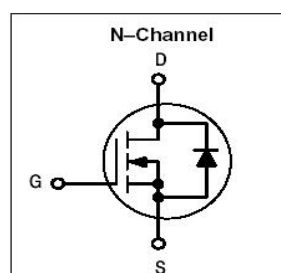
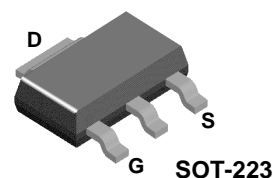
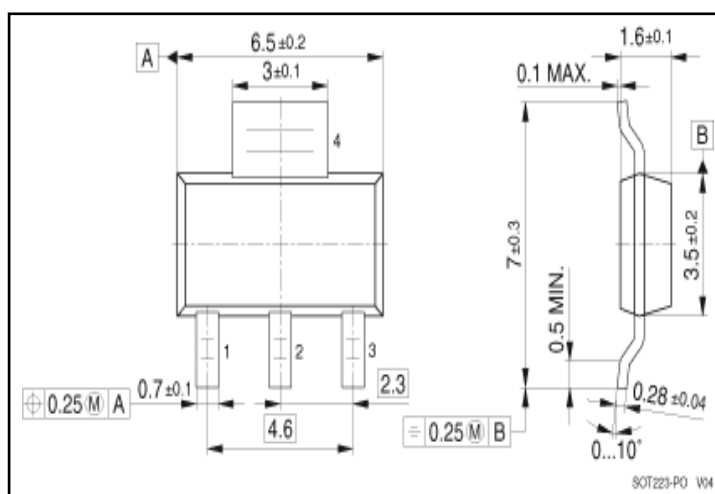
High Density Cell Design For Ultra Low OnResistance

极低的导通电阻高密度的单元设计

Improved ShootThrough FOM 改进的成型工艺

Package Dimensions 封装尺寸及外形图

Package Dimensions 封装尺寸及外形图



### Maximum Ratings and Thermal Characteristics (TA = 25°C unless otherwise noted) 25°C 极限参数和热特性

Parameter 极限参数	Symbol 符号	Limit 范围	Unit 单位	
DrainSource Voltage 漏源电压	V <sub>DS</sub>	100	V	
GateSource Voltage 栅源电压	V <sub>GS</sub>	± 20		
Continuous Drain Current 连续漏极电流	I <sub>D</sub>	2.0	A	
Pulsed Drain Current 脉冲漏极电流	I <sub>DM</sub>	5		
Maximum Power Dissipation 最大耗散功率	P <sub>D</sub>	TA = 25°C	3.1	W
		TA = 75°C	2.0	
Operating Junction and Storage Temperature Range 使用及储存温度	T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	°C	
JunctiontoAmbient Thermal Resistance (PCB mounted) 结环热阻	R <sub>θJA</sub>	125	°C/W	

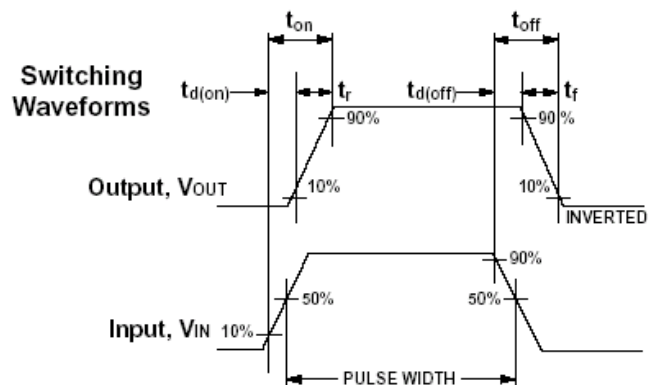
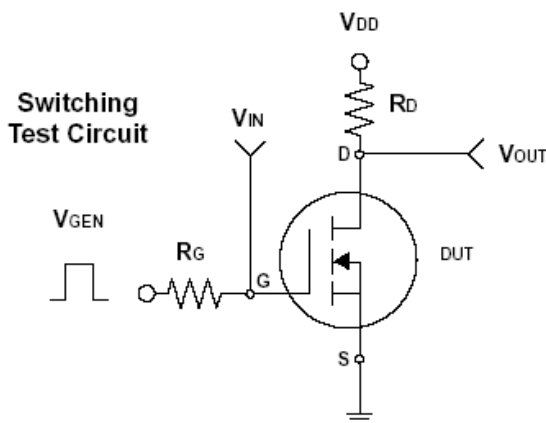
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### ELECTRICAL CHARACTERISTICS 一般电气特性

Parameter 参数	符号	Test Condition 测试条件	最小值	典型值	最大值	单位
<b>Static 静态参数</b>						
DrainSource Breakdown Voltage 漏源击穿电压	$BV_{DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	100			V
DrainSource OnState Resistance 漏源导通电阻	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 2.0A$		205	220	mΩ
DrainSource OnState Resistance 漏源导通电阻	$R_{DS(on)}$	$V_{GS} = 4.5V, I_D = 1.5A$		220	240	
Gate Threshold Voltage 开启电压	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.0	1.6	2.5	V
Zero Gate Voltage Drain Current 零栅压漏极电流	$I_{DSS}$	$V_{DS} = 60V, V_{GS} = 0V$			1	μA
Gate Body Leakage 漏极短路时截止栅电流	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA
Forward Transconductance 正向跨导	$g_{fs}$	$V_{DS} = 5V, I_D = 1A$		2.4		S
<b>Dynamic 动态参数</b>						
Total Gate Charge 栅极总电荷	$Q_g$	$V_{DS} = 50V, I_D = 2.0A$ $V_{GS} = 10V$		7.0		nC
GateSource Charge 栅源极电荷	$Q_{gs}$			0.6		
GateDrain Charge 栅漏极电荷	$Q_{gd}$			2.7		
TurnOn Delay Time 导通延迟时间	$t_{d(on)}$	$V_{DD} = 50V, R_L = 25\Omega$ $V_{GEN} = 10V, R_G = 3.0\Omega$		6.8		ns
TurnOn Rise Time 导通上升时间	$t_r$			7.5		
TurnOff Delay Time 关断延迟时间	$t_{d(off)}$			27.5		
TurnOff Fall Time 关断下降时间	$t_f$			4.5		
Input Capacitance 输入电容	$C_{iss}$	$V_{DS} = 50V, V_{GS} = 0V$ $f = 1.0MHz$		390		pF
Output Capacitance 输出电容	$C_{oss}$			17		
Reverse Transfer Capacitance 反向传输电容	$C_{rss}$			8		
<b>SourceDrain Diode 源漏二极管参数</b>						
Max. Diode Forward Current 最大正向电流	$I_S$				2.0	A
Diode Forward Voltage 正向电压	$V_{SD}$	$I_S = 1.0A, V_{GS} = 0V$			1.2	V

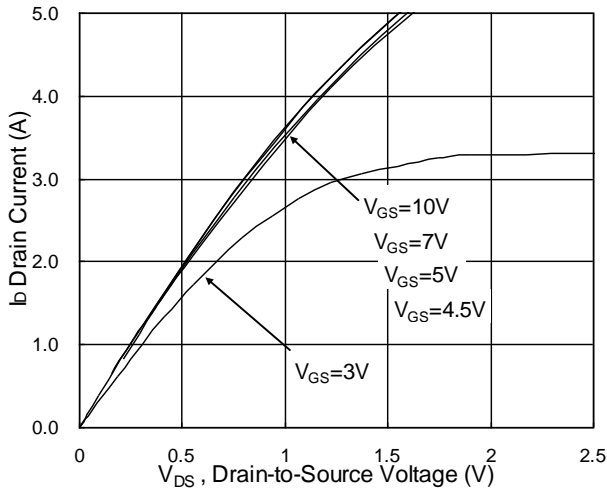
Note :

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 20Z copper.
- 2.The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
- 3.The power dissipation is limited by 150°C junction temperature
- 4.The data is theoretically the same as  $I_D$  and  $I_{DM}$  , in real applications , should be limited by total power dissipation.

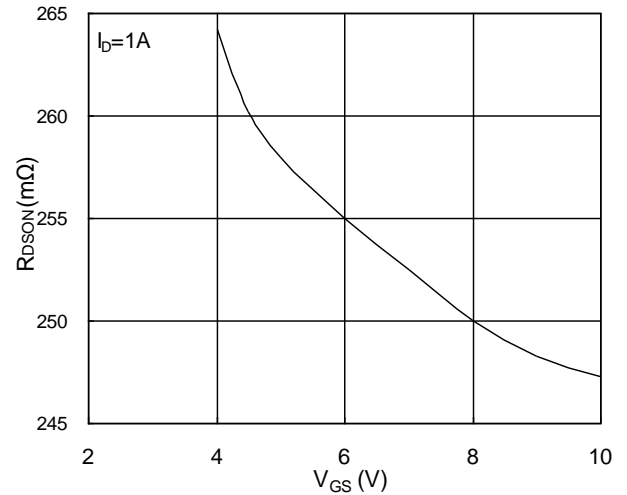


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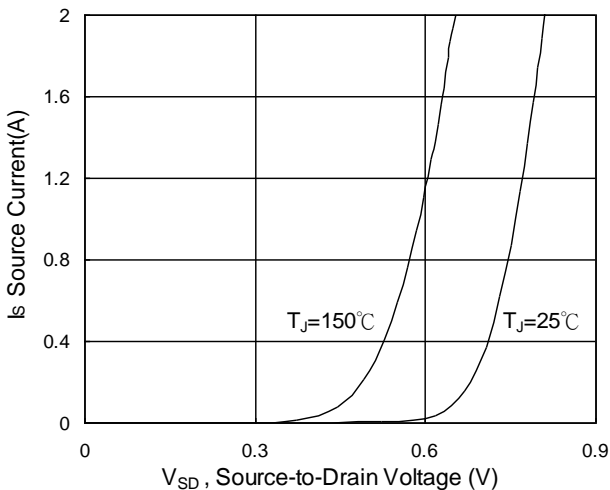
### Typical Characteristics



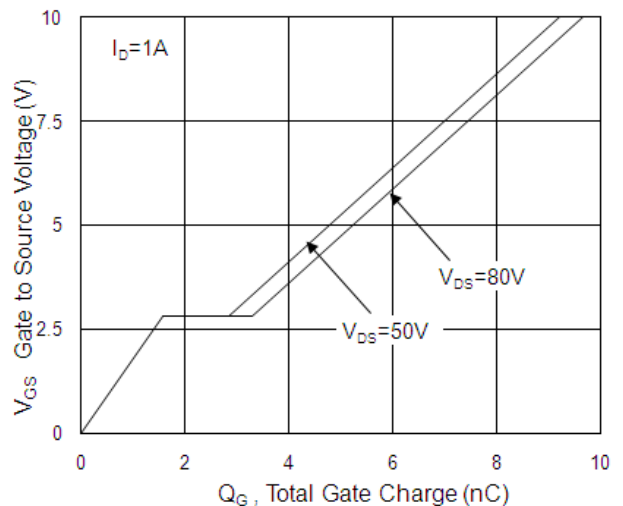
**Fig.1 Typical Output Characteristics**



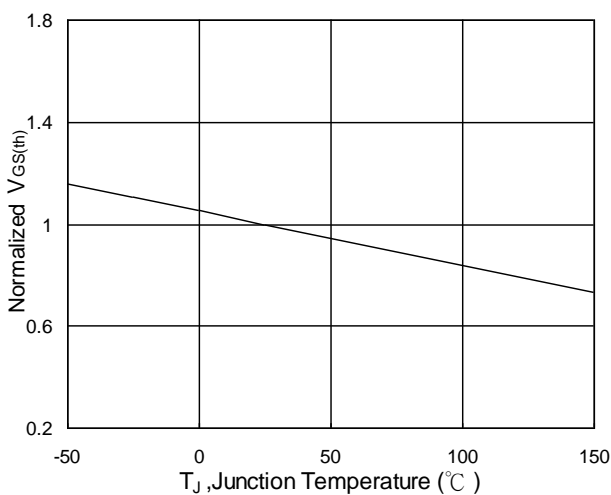
**Fig.2 On-Resistance vs. Gate-Source**



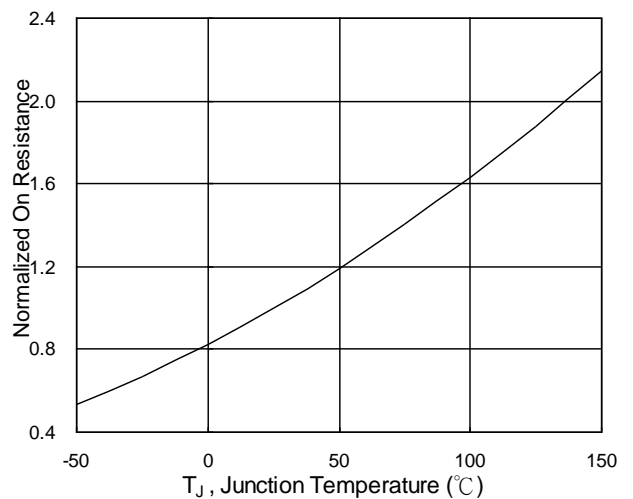
**Fig.3 Forward Characteristics of Reverse**



**Fig.4 Gate-Charge Characteristics**



**Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$**



**Fig.6 Normalized  $R_{DS(on)}$  vs.  $T_J$**